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FORM PTO-892 (REV. 2-92)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	SERIAL NO. <u>08/416100</u>	GROUP PART UNIT <u>2212</u>	ATTACHMENT TO PAPER NUMBER <u>3</u>
NOTICE OF REFERENCES CITED		Prater et al.		

## U.S. PATENT DOCUMENTS

•	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
A	3 0 1 3 4 6 7	12/61	Minsky	356	432	—
B	4 9 3 5 6 3 4	6/90	Hansma et al.	250	306	—
C	5 1 1 7 4 6 6	5/92	Buicon et al.	382	6	—
D	5 1 2 7 7 3 0	7/92	Brelje et al.	356	318	—
E	5 1 6 4 7 9 1	11/92	Kubo et al.	250	306	—
F	5 1 7 2 0 0 2	12/92	Marshall	250	306	—
G	5 2 0 6 7 0 2	4/93	Kato et al.	250	306	—
H	5 2 3 1 2 8 6	7/93	Kajimura et al.	250	306	—
I	5 2 6 0 8 2 4	11/93	OKada et al.	250	306	19 April '90
J	5 2 9 1 7 7 5	3/94	Gamble et al.	73	105	04 March '92
K	5 2 9 8 9 7 5	3/94	Khoury et al.	73	105	27 Sept. '91

## FOREIGN PATENT DOCUMENTS

•	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG	PP. SPEC.
L	6 9 8 1 9 4	11/64	Canada	Drey Fus	73	105		
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N								
O								
P								
Q								

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

R	Hipp et al., "A Stand-Alone Scanning Force and Friction Microscope", Ultramicroscopy, 42-44, 1992, pp. 1498-1503.
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U	

EXAMINER	DATE
David Y. L.	13 July 1995

\* A copy of this reference is not being furnished with this office action.  
(See Manual of Patent Examining Procedure, section 707.05 (a).)

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NOTICE OF REFERENCES CITED				08/416100	2212		
				APPLICANT(S)	Prater et al.		

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*	DOCUMENT NO.		DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE	
A	53	88	452	2/95	Harp et al.	73	105	15 Oct '93
B	53	94	741	3/95	Kajimura et al.	73	105	27 April '92
C	54	06	833	4/95	Yamamoto	73	105	13 Aug. '93
D								
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G								
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*	DOCUMENT NO.		DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG.	PP. SPEC.
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R	Jung et al., "Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens", Electronic Letters, Vol. 29, No. 3, February 1993, pp. 264-266.						
T	Martin et al., "Atomic Force Microscope-Force Mapping and Profiling on a Sub 100-Å Scale", J. Appl. Phys., 61(10), 15 May 1987, 4723-4729.						
U	van der Werf et al., "Compact Stand-Alone Atomic Force Microscope", Rev. Sci. Instrum., 64(10), October 1993, pp. 2892-2897.						

EXAMINER	DATE
<i>David Ottie</i>	<i>13 July 1995</i>

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